

**INSTITUTE OF NANO OPTOELECTRONICS**

**RESEARCH AND TECHNOLOGY (INOR)**

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**MOCVD GROWN SAMPLE REQUEST FORM**

|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Requestor Name | : |  | | | | | | | | | | | | | | | | |
|  |  |  | | | |  | |  | |  | | | |  | | |  |  |
| Contact No. | : |  | | | | Email | | : | |  | | | | Date | | | : |  |
|  |  |  | | | |  | |  | |  | | | |  | | |  |  |
| School/Company | : |  | | | | | | | | | | | | | | | | |
|  |  |  |  | | |  |  | | | | |  |  | | | | | |
| Category | : |  | INOR Staff/Student | | |  | Other Dept. | | | | : |  | | | | | | |
|  |  |  |  | | |  |  | | | | |  |  | | | | | |
| Sample Type | : |  | Powder |  | Thin Film | | | |  | | | | No. of Sample | | : |  | | |
|  |  |  |  |  |  | | | |  | | | |  | |  |  | | |
| Materials | : |  | | | | | | | | | | | | | | | | |
|  |  |  |  |  |  | | | |  | | | |  | |  |  | | |
| Substrate | : |  | | | | | | | | | | | | | | | | |

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| ***Please Tick Appropriate Box*** | | | | | | | | | |
|  | | **METAL ORGANIC CHEMICAL VAPOUR DEPOSITION [MOCVD]** | | | | | | | |
|  | | | | | | | | | |
|  |  | | | |  |  |  | | |
|  | (run per hour/standard sample) | | | |  |  |  | | |
|  |  | | | |  |  |  | | |
|  | **Structure** | | | |  |  | **Substrate** | | |
|  |  | |  | |  |  |  |  | |
|  |  | |  | Single layer |  |  |  |  | C-Plane Flat Sapphire Substrate (FSS) |
|  |  | |  |  |  |  |  |  |  |
|  |  | |  | Few layers [<5 layers] |  |  |  |  | C-Plane Patterned Sapphire Substrate (PSS) |
|  |  | |  |  |  |  |  |  |  |
|  |  | |  | Full device [LED, Photodetector & etc.] |  |  |  |  | GaN |
|  |  | |  |  |  |  |  |  |  |
|  | *\* Please attach the schematic of the planned structure with thickness.* | | | | | |  |  |  |
|  |  | | | |  |  |  |  |  |
|  |  | | | | | |  |  |  |
|  | **Expected results [e.g. Indium composition, n-doping, p-doping]:** | | | | | |  |  |  |
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| --- | --- |
| **Other information about the sample** *(e.g. sample stability/temperature)* **:** | |
|  | |
|  |  |
| **Requestor Signature:** | **Supervisor Approval:**  *(if Students, need to get the approval from Supervisor)* |